

# 54ACTQ16373

## 16-Bit Transparent Latch with TRI-STATE® Outputs

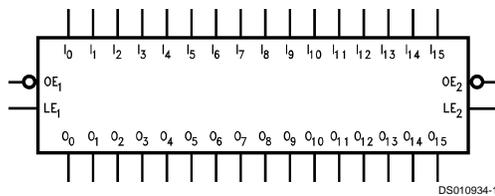
### General Description

The 'ACTQ16373 contains sixteen non-inverting latches with TRI-STATE outputs and is intended for bus oriented applications. The device is byte controlled. The flip-flops appear transparent to the data when the Latch Enable (LE) is HIGH. When LE is low, the data that meets the setup time is latched. Data appears on the bus when the Output Enable (OE) is LOW. When OE is HIGH, the outputs are in high Z state. The 'ACTQ16373 utilizes NSC Quiet Series technology to guarantee quiet output switching and improved dynamic threshold performance. FACT Quiet Series™ features GTO™ output control for superior performance.

### Features

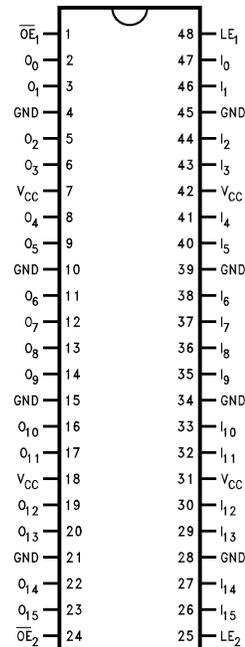
- Utilizes NSC FACT Quiet Series technology
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Separate control logic for each byte
- 16-bit version of the 'ACTQ373
- Outputs source/sink 24 mA
- Standard Microcircuit Drawing (SMD) 5962-9561801

### Logic Symbol



### Connection Diagram

Pin Assignment for CERPAK



### Pin Description

Pin Names	Description
$\overline{OE}_n$	Output Enable Input (Active Low)
$LE_n$	Latch Enable Input
$I_0-I_{15}$	Inputs
$O_0-O_{15}$	Outputs

TRI-STATE® is a registered trademark of National Semiconductor Corporation.  
 GTO™ is a trademarks of National Semiconductor Corporation.  
 FACT™ and FACT Quiet Series™ are trademarks of Fairchild Semiconductor Corporation.

## Functional Description

The ACTQ16373 contains sixteen D-type latches with TRI-STATE standard outputs. The device is byte controlled with each byte functioning identically, but independent of the other. Control pins can be shorted together to obtain full 16-bit operation. The following description applies to each byte. When the Latch Enable ( $LE_n$ ) input is HIGH, data on the  $D_n$  enters the latches. In this condition the latches are transparent, i.e., a latch output will change states each time its D input changes. When  $LE_n$  is LOW, the latches store information that was present on the D inputs a setup time preceding the HIGH-to-LOW transition of  $LE_n$ . The TRI-STATE standard outputs are controlled by the Output Enable ( $\overline{OE}_n$ ) input. When  $\overline{OE}_n$  is LOW, the standard outputs are in the 2-state mode. When  $\overline{OE}_n$  is HIGH, the standard outputs are in the high impedance mode but this does not interfere with entering new data into the latches.

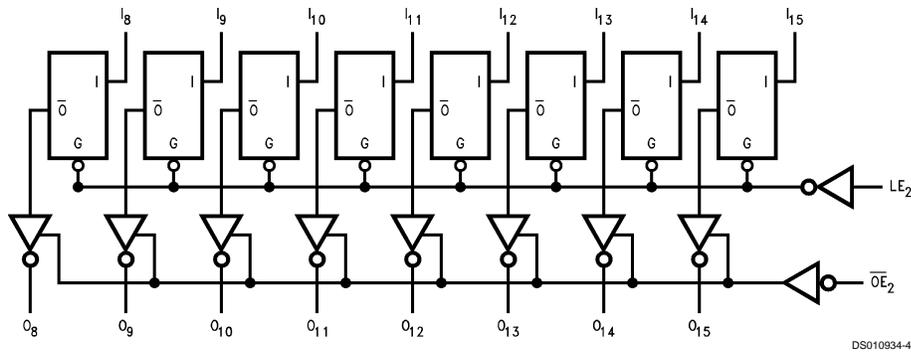
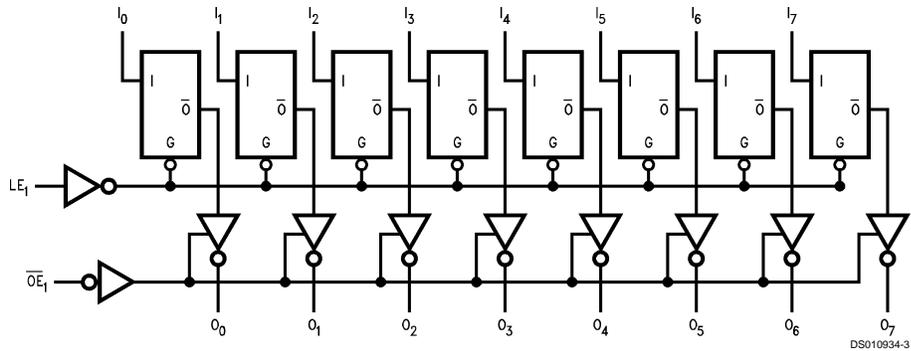
## Truth Table

Inputs			Outputs
$LE_1$	$\overline{OE}_1$	$I_0-I_7$	$O_0-O_7$
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	(Previous)

Inputs			Outputs
$LE_2$	$\overline{OE}_2$	$I_8-I_{15}$	$O_8-O_{15}$
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	(Previous)

H = High Voltage Level  
 L = Low Voltage Level  
 X = Immaterial  
 Z = High Impedance  
 Previous = previous output prior to HIGH to LOW transition of LE

## Logic Diagrams



## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage ( $V_{CC}$ )	-0.5V to +7.0V
DC Input Diode Current ( $I_{IK}$ )	
$V_I = -0.5V$	-20 mA
$V_I = V_{CC} + 0.5V$	+20 mA
DC Output Diode Current ( $I_{OK}$ )	
$V_O = -0.5V$	-20 mA
$V_O = V_{CC} + 0.5V$	+20 mA
DC Output Voltage ( $V_O$ )	-0.5V to $V_{CC} + 0.5V$
DC Output Source/Sink Current ( $I_O$ )	+50 mA
DC $V_{CC}$ or Ground Current	+50 mA
per Output Pin	
Junction Temperature	
CDIP	+175°C
Storage Temperature	-65°C to +150°C

## Recommended Operating Conditions

Supply Voltage ( $V_{CC}$ )	
'ACTQ	4.5V to 5.5V
Input Voltage ( $V_I$ )	0V to $V_{CC}$
Output Voltage ( $V_O$ )	0V to $V_{CC}$
Operating Temperature ( $T_A$ )	
54ACTQ	-55°C to +125°C
Minimum Input Edge Rate (dV/dt)	
'ACTQ Devices	125 mV/ns
$V_{IN}$ from 0.8V to 2.0V	
$V_{CC}$ @ 4.5V, 5.5V	

**Note 1:** Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

## DC Electrical Characteristics for 'ACTQ Family Devices

Symbol	Parameter	$V_{CC}$ (V)	54ACTQ	Units	Conditions
			$T_A =$ -55°C to +125°C		
			Guaranteed Limits		
$V_{IH}$	Minimum High Input Voltage	4.5	2.0	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
		5.5	2.0		
$V_{IL}$	Maximum Low Input Voltage	4.5	0.8	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
		5.5	0.8		
$V_{OH}$	Minimum High Output Voltage	4.5	4.4	V	$I_{OUT} = -50 \mu A$
		5.5	5.4		
		4.5	3.70		
$V_{OL}$	Maximum Low Output Voltage	4.5	0.1	V	$I_{OUT} = 50 \mu A$
		5.5	0.1		
		4.5	0.50		
$I_{OZ}$	Maximum TRI-STATE Leakage Current	5.5	±10.0	$\mu A$	$V_I = V_{IL}, V_{IH}$ $V_O = V_{CC}, GND$
$I_{IN}$	Maximum Input Leakage Current	5.5	±1.0	$\mu A$	$V_I = V_{CC}, GND$
$I_{CCT}$	Maximum $I_{CC}$ /Input	5.5	1.6	mA	$V_I = V_{CC} - 2.1V$
$I_{CC}$	Max Quiescent Supply Current	5.5	160.0	$\mu A$	$V_{IN} = V_{CC}$ or GND (Note 7)
$I_{OLD}$	Minimum Dynamic Output Current (Note 3)	5.5	50	mA	$V_{OLD} = 1.65V$ Max
			50	mA	$V_{OHD} = 3.85V$ Min
$V_{OLP}$	Quiet Output Maximum Dynamic $V_{OL}$	5.0	0.8	V	(Notes 4, 5)

## DC Electrical Characteristics for 'ACTQ Family Devices (Continued)

Symbol	Parameter	V <sub>CC</sub> (V)	54ACTQ		Units	Conditions
			T <sub>A</sub> = -55°C to +125°C			
			Guaranteed Limits			
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	5.0	-0.8		V	(Notes 4, 5)

**Note 2:** All outputs loaded; thresholds associated with output unders test.

**Note 3:** Maximum test duration 2.0 ms; one output loaded at a time.

**Note 4:** Maximum number of outputs that can switch simultaneously is n. (n - 1) outputs are switched LOW and one output held LOW.

**Note 5:** Maximum number of outputs that can switch simultaneously is n. (n - 1) outputs are switched HIGH and one output held HIGH.

**Note 6:** Max number of data inputs (n) switching, (n - 1) input switching 0V to 3V ('ACTQ). Input under test switching 3V to threshold (V<sub>ILD</sub>)

**Note 7:** I<sub>CC</sub> for 54ACTQ @ 25°C is identical to 74ACTQ @ 25°C.

## AC Electrical Characteristics:

Symbol	Parameter	V <sub>CC</sub> (V) (Note 8)	54ACTQ		Units
			T <sub>A</sub> = -55°C to +125°C C <sub>L</sub> = 50 pF		
			Min	Max	
t <sub>PLH</sub>	Propagation Delay	5.0	3.0	10.5	ns
t <sub>PHL</sub>	D <sub>n</sub> to O <sub>n</sub>		3.0	10.0	
t <sub>PLH</sub>	Propagation Delay	5.0	3.0	11.0	ns
t <sub>PHL</sub>	LE to O <sub>n</sub>		3.0	10.0	
t <sub>PZH</sub>	Output Enable	5.0	2.5	10.0	ns
t <sub>PZL</sub>	Delay		2.5	11.0	
t <sub>PHZ</sub>	Output Disable	5.0	2.0	9.0	ns
t <sub>PLZ</sub>	Delay		2.0	9.0	

**Note 8:** Voltage Range 5.0 is 5.0V ± 0.5V.

### AC Operating Requirements:

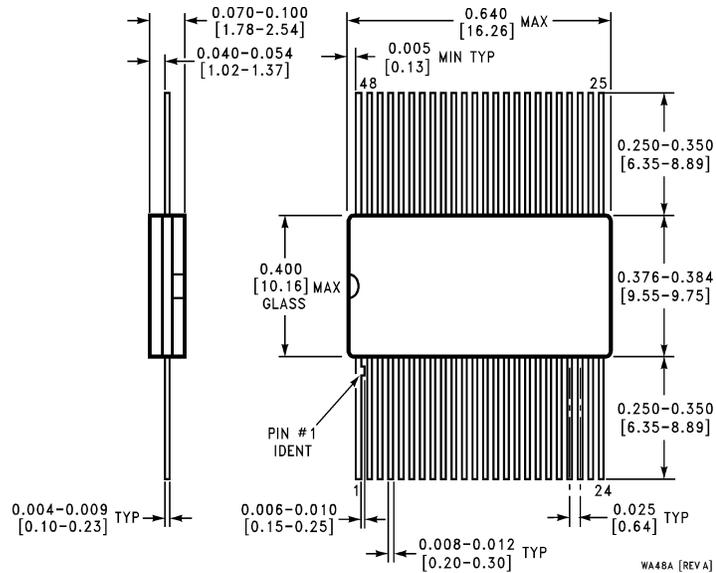
Symbol	Parameter	V <sub>CC</sub> (V) (Note 9)	54ACTQ	Units
			-55°C to +125°C 50 pF	
			Guaranteed Minimum	
t <sub>s</sub>	Setup Time, HIGH or LOW, Input to Clock	5.0	3.0	ns
t <sub>h</sub>	Hold time, High or LOW, Input to Clock	5.0	1.5	ns
t <sub>w</sub>	CS Pulse Width, HIGH or LOW	5.0	4.0	ns

Note 9: Voltage Range 5.0 is 5.0V ± 0.5V

### Capacitance

Symbol	Parameter	Typ	Units	Conditions
C <sub>IN</sub>	Input Capacitance	4.5	pF	V <sub>CC</sub> = 5.0V
C <sub>PD</sub>	Power Dissipation	95	pF	V <sub>CC</sub> = 5.0V

**Physical Dimensions** inches (millimeters) unless otherwise noted



**48-Lead CERPAK  
NS Package Number WA48A**

**LIFE SUPPORT POLICY**

NATIONAL'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF NATIONAL SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



**National Semiconductor Corporation**  
Americas  
Tel: 1-800-272-9959  
Fax: 1-800-737-7018  
Email: support@nsc.com

**National Semiconductor Europe**  
Fax: +49 (0) 1 80-530 85 86  
Email: europe.support@nsc.com  
Deutsch Tel: +49 (0) 1 80-530 85 85  
English Tel: +49 (0) 1 80-532 78 32  
Français Tel: +49 (0) 1 80-532 93 58  
Italiano Tel: +49 (0) 1 80-534 16 80

**National Semiconductor Asia Pacific Customer Response Group**  
Tel: 65-2544466  
Fax: 65-2504466  
Email: sea.support@nsc.com

**National Semiconductor Japan Ltd.**  
Tel: 81-3-5620-6175  
Fax: 81-3-5620-6179

www.national.com